Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/808,287	KAMADA ET AL.	
Examiner	Art Unit	

Chun-Kuan (Mike) Lee

2181

SEARCHED					
Class	Subclass	Date	Examiner		
710	22-28	3/30/2007	CHUN- KUAN Lee		
710	48-50	3/30/2007			
710	52	3/30/2007			
· 710	57	3/30/2007			
710	60	3/30/2007			
710	260-262	3/30/2007	V'		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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(INCLUDING SEARCH			
(EAST) US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB Inventor search on PALM and eDAN	3/30/2007	EXMR CHUN- KUAN Lee	
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